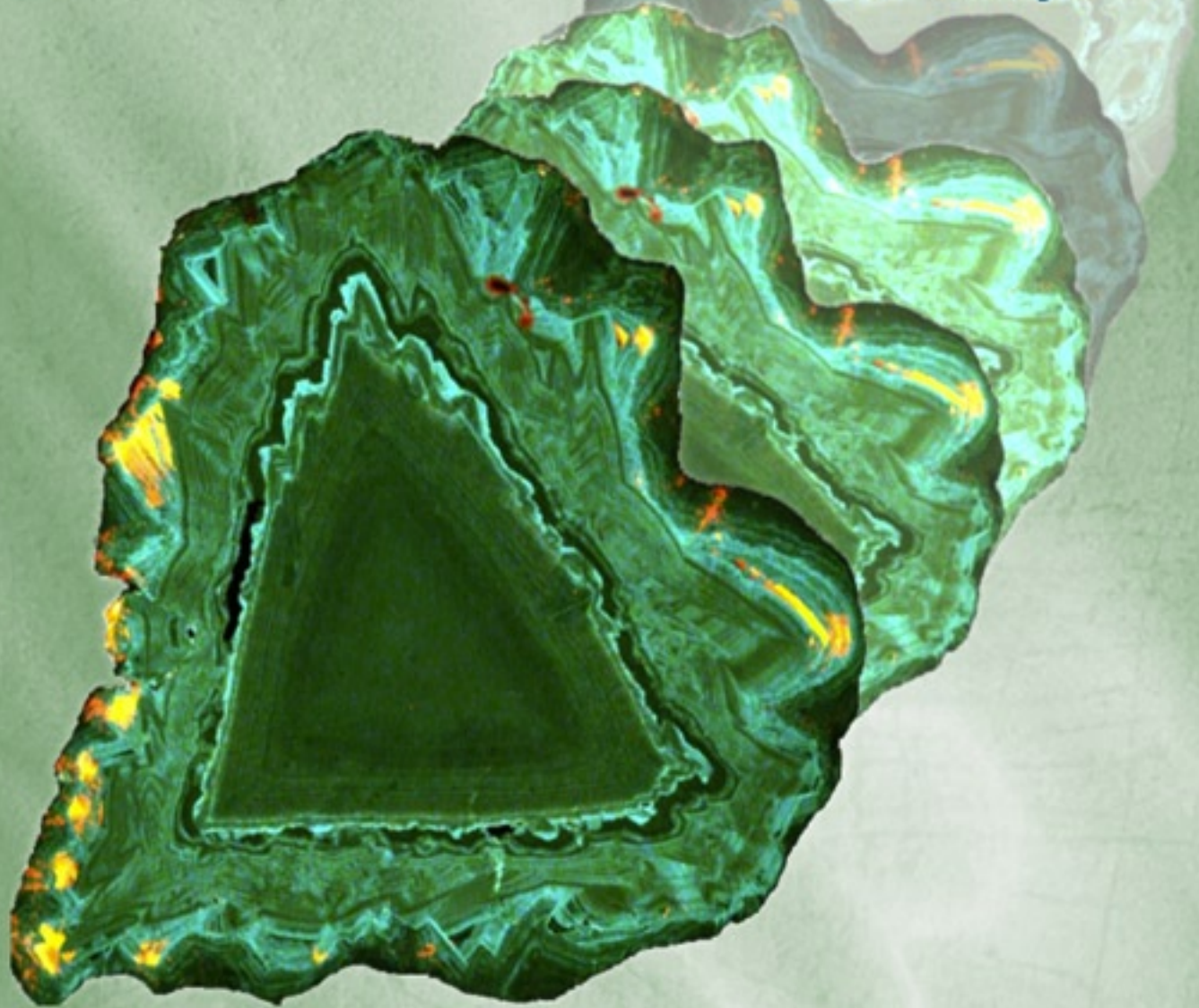


xCLent

X-ray and Cathodoluminescence Microanalyser



New combined

X-ray and CL

acquisition technique

- Simultaneous X-ray (WDS and EDS) and CL mapping with full CL spectrum at each pixel

JEOL

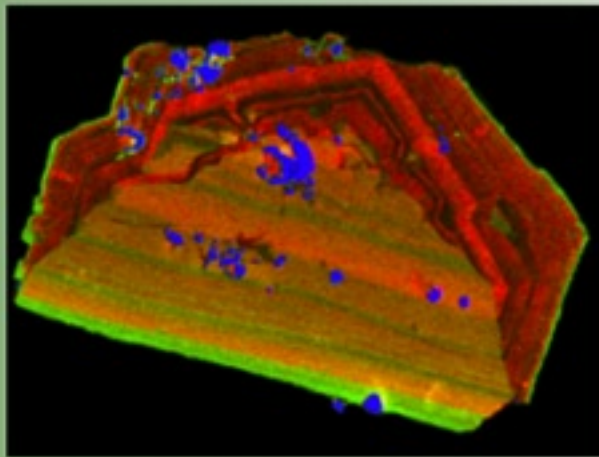
Serving Advanced Technology



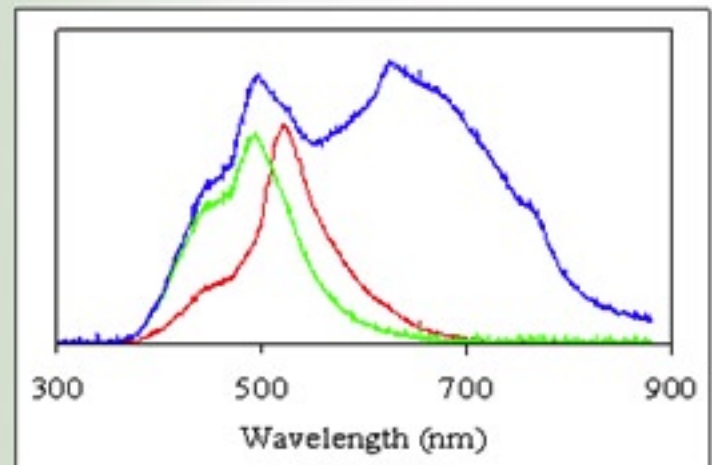
Optical coupling to JEOL 8100/8200 electron probe microanalyzer



The XCLent system is easy to use, seamlessly integrated into the JEOL EPMA menu structure. The number of channels acquired can be selected.



Grain of Apatite with aluminium inclusions shown in blue and single CL wavelengths 500 and 600 nm shown in green and red respectively.



Cathodoluminescence spectra can be extracted from either a single pixel or a selected area. Kimberlite diamond CL spectra are shown here.

Specifications

Hardware

- Peltier cooled single channel spectrometer including 2048 element linear CCD
- PCI-bus A/D card with 2MHz sampling
- 200 micron, 2m long silica fibre with SMA connectors
- Collimating Lens and coupling to JEOL monocular eyepiece
- PCI Digital IO board for communication with EPMA
- Interface card for JEOL electron microprobe bus
- PC running Microsoft Windows XP to control capture and display data
- Manual for installation of system and software

*Specifications subject to change without notice

Software

- [xCLent server](#) – software to control spectrometer acquisition and synchronisation with x-ray mapping, both beam and stage mapping are supported by this software.
- [xCL-image](#) - software for displaying combined x-ray and cathodoluminescence maps, elemental scatter plots, elemental ternary diagrams.

Options

- Second PC for analysing data while the microprobe is collecting maps
- Second spectrometer optimised optical response for studying specific customer problems

JEOL

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